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Data Sheet

October 2013

N-Channel UltraFET Power MOSFET 55 V, 75 A, 8 mΩ

These N-Channel power MOSFETs are manufactured using the innovative UltraFET process. This advanced process technology achieves the lowest possible onresistance per silicon area, resulting in outstanding performance. This device is capable of withstanding high energy in the avalanche mode and the diode exhibits very low reverse recovery time and stored charge. It was designed for use in applications where power efficiency is important, such as switching regulators, switching converters, motor drivers, relay drivers, low-voltage bus switches, and power management in portable and batteryoperated products.

Formerly developmental type TA75344.

Ordering Information

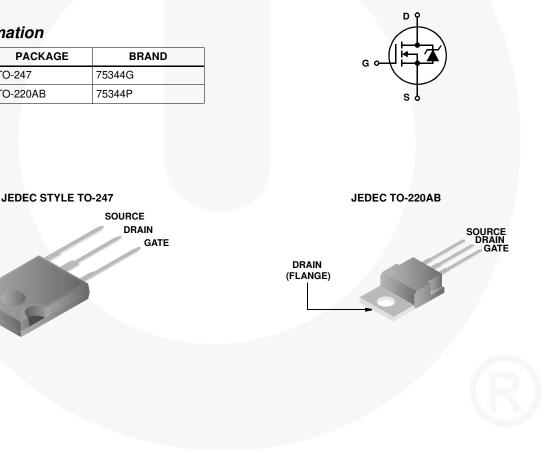
Packaging

PART NUMBER	PACKAGE	BRAND
HUF75344G3	TO-247	75344G
HUF75344P3	TO-220AB	75344P

Features

- 75A, 55V
- Simulation Models
 - Temperature Compensated PSPICE® and SABER™ Models
 - Thermal Impedance PSPICE and SABER Models Available on the web at: www.fairchildsemi.com
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- Related Literature
 - TB334, "Guidelines for Soldering Surface Mount Components to PC Boards"

Symbol



Product reliability information can be found at http://www.fairchildsemi.com/products/discrete/reliability/index.html For severe environments, see our Automotive HUFA series.

All Fairchild semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

DRAIN (TAB)

Absolute Maximum Ratings $T_{C} = 25^{\circ}C$, Unless Otherwise Specified

		UNITS
Drain to Source Voltage (Note 1)V _{DSS}	55	V
Drain to Gate Voltage (R _{GS} = 20kΩ) (Note 1)V _{DGR}	55	V
Gate to Source Voltage	±20	V
Drain Current		
Continuous (Figure 2)	75	A
Pulsed Drain Current	Figure 4	
Pulsed Avalanche Rating EAS	Figure 6	
Power Dissipation PD	285	W
Derate Above 25 ^o C	1.90	W/ ^o C
Operating and Storage Temperature	-55 to 175	°C
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s	300	°C
Package Body for 10s, See Techbrief 334 T _{pkg}	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

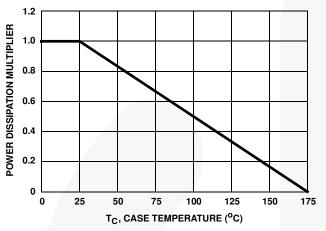
1. $T_J = 25^{\circ}C$ to $150^{\circ}C$.

PARAMETER	SYMBOL	TEST	CONDITIONS	MIN	TYP	MAX	UNITS
OFF STATE SPECIFICATIONS							
Drain to Source Breakdown Voltage	BV _{DSS}	I _D = 250μA, V _{GS} =	0V (Figure 11)	55	-	-	V
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 50V, V_{GS} = 0V$		-	-	1	μA
		V _{DS} = 45V, V _{GS} =	0V, T _C = 150 ^o C	-	-	250	μA
Gate to Source Leakage Current	I _{GSS}	V _{GS} = ±20V		-	-	±100	nA
ON STATE SPECIFICATIONS		1			1		
Gate to Source Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D} = 25$	50μA (Figure 10)	2	-	4	V
Drain to Source On Resistance	rDS(ON)	I _D = 75A, V _{GS} = 10	V (Figure 9)	-	6.5	8.0	mΩ
THERMAL SPECIFICATIONS					1		
Thermal Resistance Junction to Case	$R_{\theta JC}$	(Figure 3)		-	-	0.52	oC/M
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	TO-247 TO-220		-	-	30	°C/W
				- \	-	62	oC/M
SWITCHING SPECIFICATIONS ($V_{GS} = 10$)	/)			7	1		
Turn-On Time	ton	$\label{eq:VD} \begin{array}{l} V_{DD} = 30V, \ I_{D} \cong 75A, \\ R_{L} = 0.4\Omega, \ V_{GS} = 10V, \\ R_{GS} = 3.0\Omega \end{array}$		-	-	187	ns
Turn-On Delay Time	t _{d(ON)}			-	13	7 -	ns
Rise Time	tr			-	125	-	ns
Turn-Off Delay Time	t _{d(OFF)}			-	46	-	ns
Fall Time	t _f			-	57	-	ns
Turn-Off Time	tOFF			-	-	147	ns
GATE CHARGE SPECIFICATIONS		I.		/			
Total Gate Charge	Q _{g(TOT)}	$V_{GS} = 0V$ to 20V	V _{DD} = 30V,	-	175	210	nC
Gate Charge at 10V	Q _{g(10)}	$V_{GS} = 0V$ to $10V$	$I_{\rm D} \cong 75{\rm A},$	-	90	108	nC
Threshold Gate Charge	Q _{g(TH)}	$V_{GS} = 0V$ to 2V	$- R_{L} = 0.4\Omega$ $- I_{g(REF)} = 1.0mA$	-	5.9	7.0	nC
Gate to Source Gate Charge	Q _{gs}	(Figure 13)	-	14	-	nC	
Reverse Transfer Capacitance	Q _{gd}			-	39	-	nC
CAPACITANCE SPECIFICATIONS	•	-					·
Input Capacitance	C _{ISS}	f _ 1MU7		-	pF		
Output Capacitance	C _{OSS}			-	1170	-	pF
Reverse Transfer Capacitance	C _{RSS}				pF		

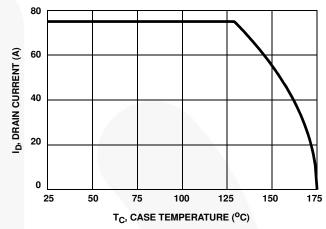
SYMBOL PARAMETER **TEST CONDITIONS** MIN TYP MAX Source to Drain Diode Voltage $I_{SD} = 75A$ 1.25 V_{SD} _ **Reverse Recovery Time** t_{rr} $I_{SD} = 75A$, $dI_{SD}/dt = 100A/\mu s$ _ 105 -**Reverse Recovered Charge** $I_{SD} = 75A, dI_{SD}/dt = 100A/\mu s$ 210 Q_{RR} --

Source to Drain Diode Specifications

Typical Performance Curves







UNITS

V

ns

nC

FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

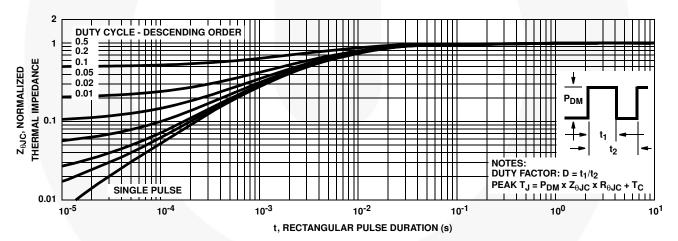
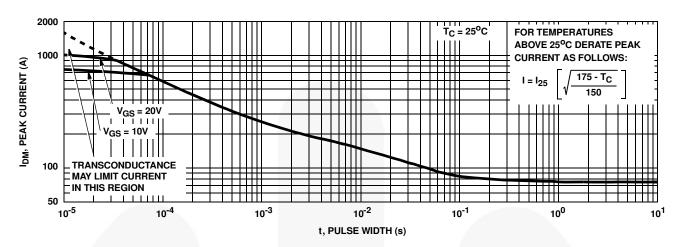


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

Typical Performance Curves (Continued)





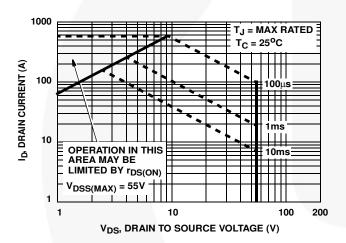


FIGURE 5. FORWARD BIAS SAFE OPERATING AREA

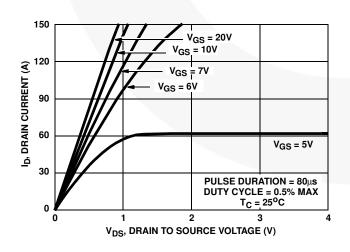
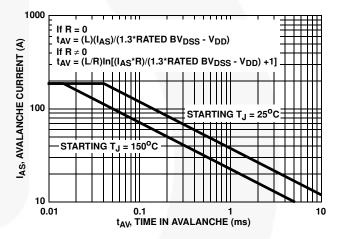


FIGURE 7. SATURATION CHARACTERISTICS



NOTE: Refer to Fairchild Application Notes AN9321 and AN9322. FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

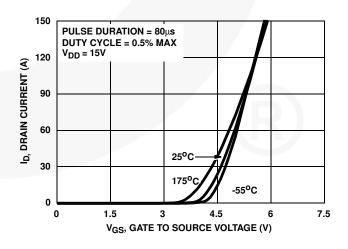
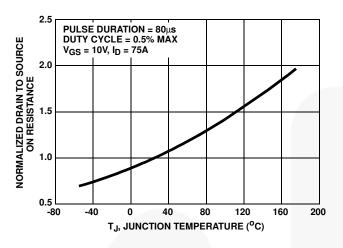


FIGURE 8. TRANSFER CHARACTERISTICS

Typical Performance Curves (Continued)





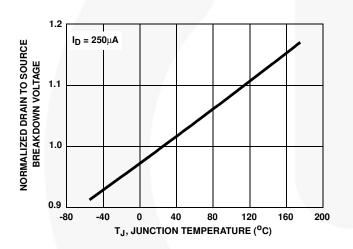


FIGURE 11. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

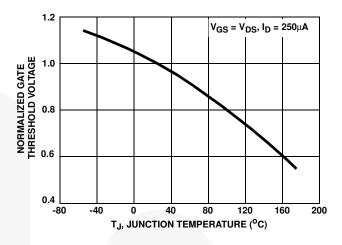


FIGURE 10. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

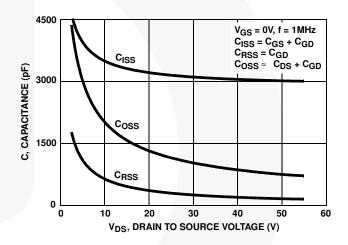
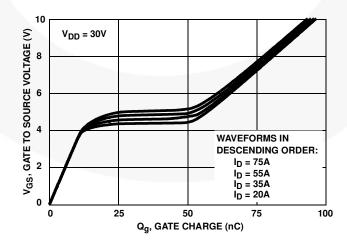


FIGURE 12. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE





Test Circuits and Waveforms

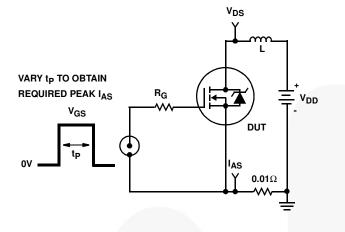


FIGURE 14. UNCLAMPED ENERGY TEST CIRCUIT

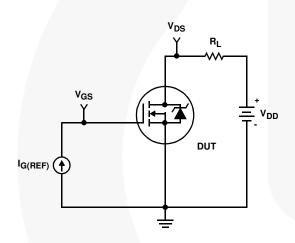
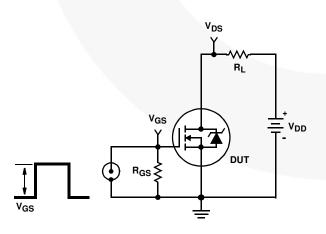


FIGURE 16. GATE CHARGE TEST CIRCUIT





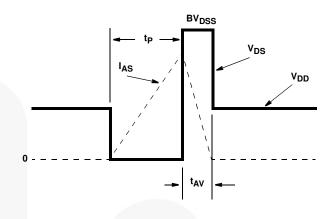


FIGURE 15. UNCLAMPED ENERGY WAVEFORMS

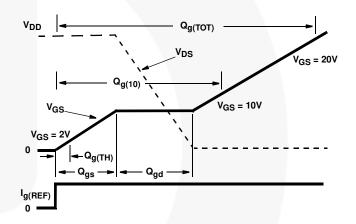


FIGURE 17. GATE CHARGE WAVEFORM

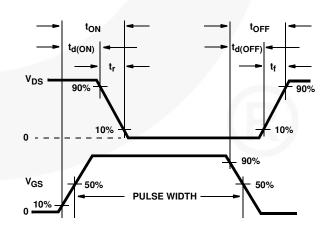
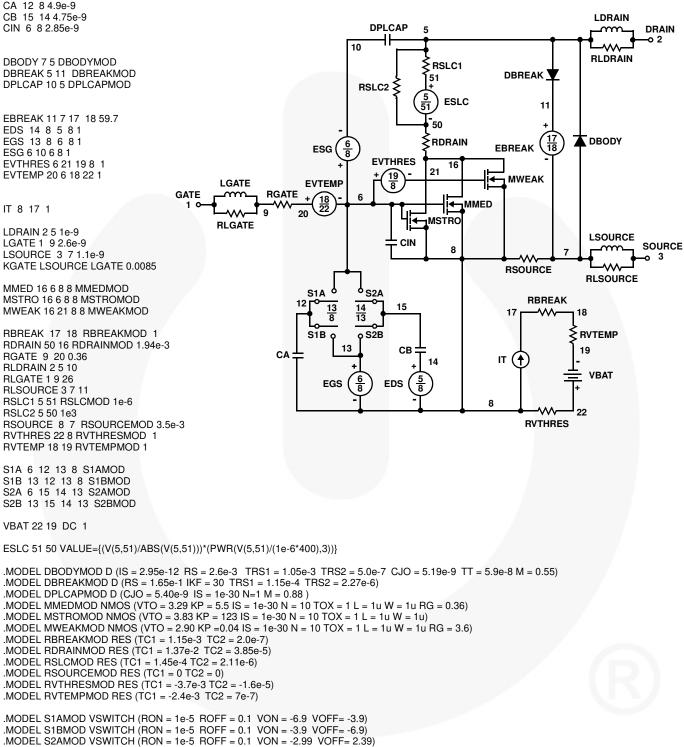


FIGURE 19. RESISTIVE SWITCHING WAVEFORMS

PSPICE Electrical Model

.SUBCKT HUF75337 2 1 3 : rev 3 Feb 1999



.MODEL S2BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = 2.39 VOFF= -2.99)

.ENDS

NOTE: For further discussion of the PSPICE model, consult A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options: IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley,

SABER Electrical Model

REV 3 February 1999 template huf75344 n2, n1, n3 electrical n2, n1, n3 var i iscl d..model dbodymod = (is = 2.95e-12, cjo = 5.19e-9, tt = 5.90e-8, m = 0.55) d..model dbreakmod = () LDRAIN DPLCAP 5 DRAIN d..model dplcapmod = (cjo = 5.40e-9, is = 1e-30, n = 1, m = 0.88) m..model mmedmod = (type=_n, vto = 3.29, kp = 5.5, is = 1e-30, tox = 1) o 2 10 m..model mstrongmod = (type=_n, vto = 3.83, kp = 123, is = 1e-30, tox = 1) RLDRAIN ERSLC1 m..model mweakmod = (type=_n, vto = 2.90, kp = 0.04, is = 1e-30, tox = 1) RDBREAK sw_vcsp..model s1amod = (ron = 1e-5, roff = 0.1, von = -6.9, voff = -3.9) 51 RSLC2≥ sw vcsp..model s1bmod = (ron = 1e-5, roff = 0.1, von = -3.9, voff = -6.9) 72 RDBODY 5 sw_vcsp..model s2amod = (ron = 1e-5, roff = 0.1, von = -2.99, voff = 2.39) Ŧ ISCL sw_vcsp..model s2bmod = (ron = 1e-5, roff = 0.1, von = 2.39, voff = -2.99) DBREAK 50 c.ca n12 n8 = 4.9e-9 ERDRAIN 71 <u>6</u> 8 c.cb n15 n14 = 4.75e-9 ESG 11 c.cin n6 n8 = 2.85e-9 **EVTHRES** 16 21 <u>19</u> 8 MWEAK EVTEMP LGATE d.dbody n7 n71 = model=dbodymod DBODY RGATE GATE d.dbreak n72 n11 = model=dbreakmod 6 18 22 EBREAK I ← MMED d.dplcap n10 n5 = model=dplcapmod 1 ¢ 9 20 *** RLGATE i.it n8 n17 = 1 18 LSOURCE CIN SOURCE 8 I.Idrain n2 n5 = 1e-9 o - 3 $1 \log t = 2 \log 1$ RSOURCE RLSOURCE l.lsource n3 n7 = 1.1e-9 k.kl i(l.lgate) i(l.lsource) = I(l.lgate), I(l.lsource), 0.0085 ^oS2/ RBREAK <u>14</u> 13 15 17 \sim 18 m.mmed n16 n6 n8 n8 = model=mmedmod, I = 1u, w = 1u m.mstrong n16 n6 n8 n8 = model=mstrongmod, I = 1u, w = 1u RVTEMP o S2B S1B m.mweak n16 n21 n8 n8 = model=mweakmod, I = 1u, w = 1u 13 CB 19 CA: IT 14 res.rbreak n17 n18 = 1, tc1 = 1.15e-3, tc2 = 2e-7 res.rdbody n71 n5 = 2.6e-3, tc1 = 1.05e-3, tc2 = 5e-7 VBAT FGS <u>6</u> 8 FDS 5 res.rdbreak n72 n5 = 1.65e-1, tc1 = 1.15e-4, tc2 = 2.27e-6 res.rdrain n50 n16 = 1.94e-3, tc1 = 1.37e-2, tc2 = 3.85e-5 8 res.rgate n9 n20 = 0.3622 res.rldrain n2 n5 = 10 RVTHRES res.rlgate n1 n9 = 26 res.rlsource n3 n7 = 11 res.rslc1 n5 n51 = 1e-6, tc1 = 1.45e-4, tc2 = 2.11e-6 res.rslc2 n5 n50 = 1e3 res.rsource n8 n7 = 3.5e-3, tc1 = 0, tc2 = 0 res.rvtemp n18 n19 = 1, tc1 = -2.4e-3, tc2 = 7e-7 res.rvthres n22 n8 = 1, tc1 = -3.7e-3, tc2 = -1.6e-5 spe.ebreak n11 n7 n17 n18 = 59.7 spe.eds n14 n8 n5 n8 = 1 spe.egs n13 n8 n6 n8 = 1 spe.esg n6 n10 n6 n8 = 1 spe.evtemp n20 n6 n18 n22 = 1 spe.evthres n6 n21 n19 n8 = 1 sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc = 1 equations { i(n51 - n50) + = iscliscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/400))** 3))

SPICE Thermal Model

REV 5 February 1999

HUF75344

CTHERM1 th 6 5.0e-3 CTHERM2 6 5 1.0e-2 CTHERM3 5 4 1.3e-2 CTHERM4 4 3 1.5e-2 CTHERM5 3 2 2.2e-2 CTHERM6 2 tl 8.5e-2

RTHERM1 th 6 6.0e-4 RTHERM2 6 5 3.5e-3 RTHERM3 5 4 2.5e-2 RTHERM4 4 3 4.8e-2 RTHERM5 3 2 1.6e-1 RTHERM6 2 tl 1.8e-1

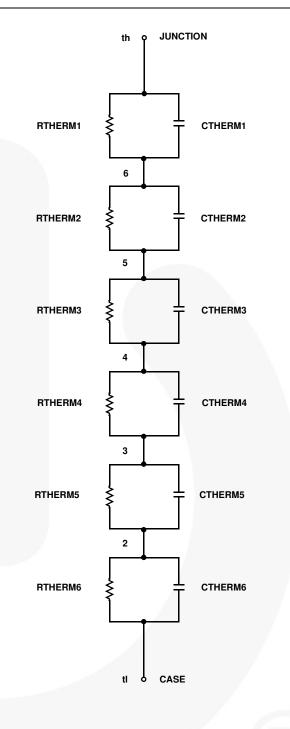
SABER Thermal Model

SABER thermal model HUF75344

template thermal_model th tl thermal_c th, tl

ctherm.ctherm1 th 6 = 5.0e-3ctherm.ctherm2 6 5 = 1.0e-2ctherm.ctherm3 5 4 = 1.3e-2ctherm.ctherm4 4 3 = 1.5e-2ctherm.ctherm5 3 2 = 2.2e-2ctherm.ctherm6 2 tl = 5.5e-2 rtherm.rtherm1 th 6 = 6.0e-4

rtherm.rtherm2 6 5 = 3.5e-3 rtherm.rtherm3 5 4 = 2.5e-2 rtherm.rtherm4 4 3 = 4.8e-2 rtherm.rtherm5 3 2 = 1.6e-1 rtherm.rtherm6 2 tl = 1.8e-1 }





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Dual Cool™_	Marking Small Speakers Sound Louder		Ti
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EfficentMax™	MegaBuck™	SignalWise™	T
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